United States Patent [19]

Friedman

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[54]	X-CONTROL MEASURING GAUGE	
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[**]	Term:	14 Years
[21]	Appl. No.:	437,993
	U.S. Cl	Nov. 20, 1989
[56] References Cited U.S. PATENT DOCUMENTS		
D. 238,395 1/1976 Miranda et al		

OTHER PUBLICATIONS

IBM Technical Disclosure Bulletin, Calibration Tool, 5/1967, p. 1733.

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[57] . CLAIM

The ornamental design for x-control measuring gauge, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view with all sides being identical of a x-control measuring gauge showing my new design, drawn on a slightly enlarged scale;

FIG. 2 is a elevational view showing one of the four identical side views;

FIG. 3 is a top plan view; and

FIG. 4 is a bottom plan view thereof.

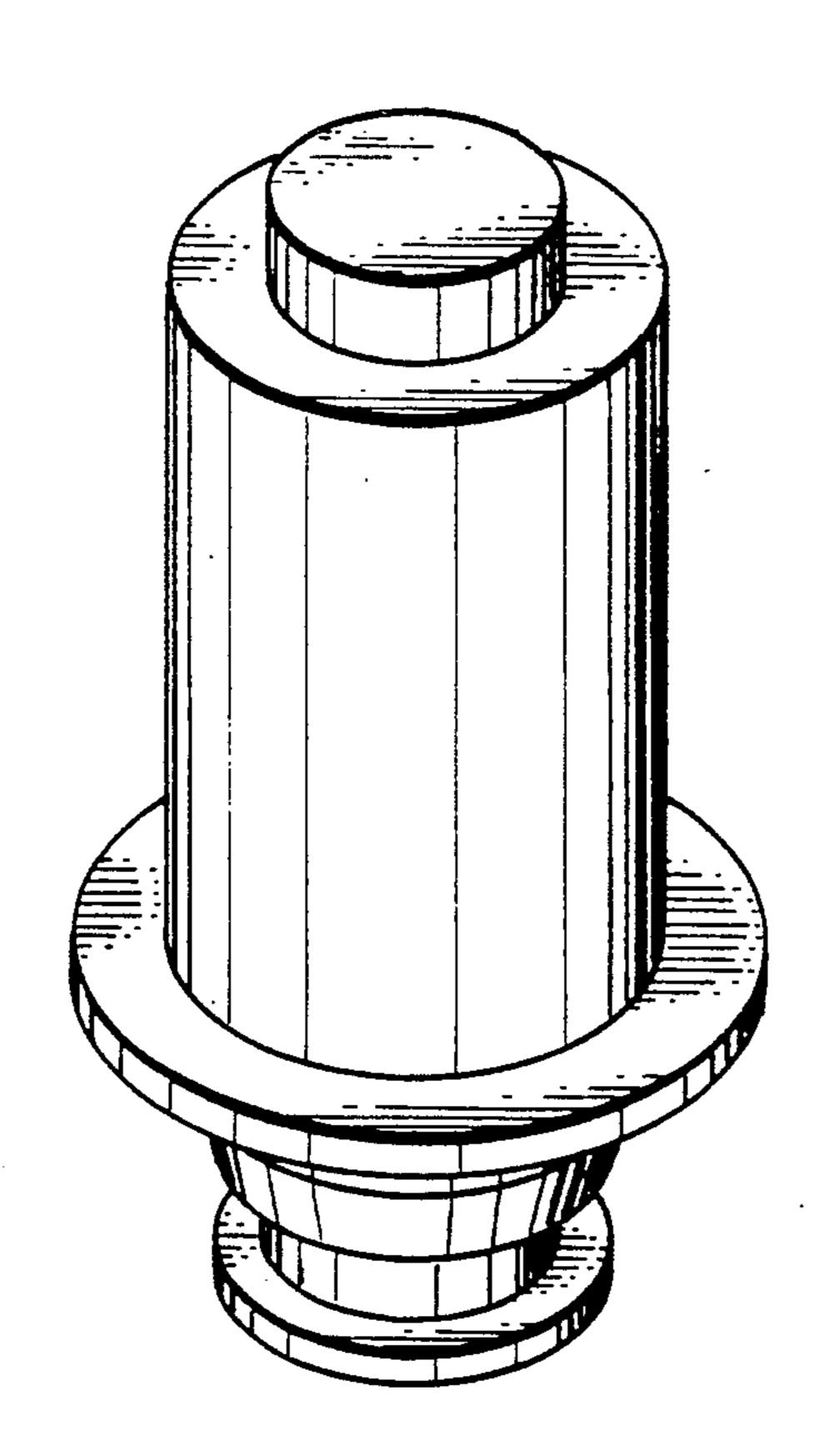


Fig. 1.

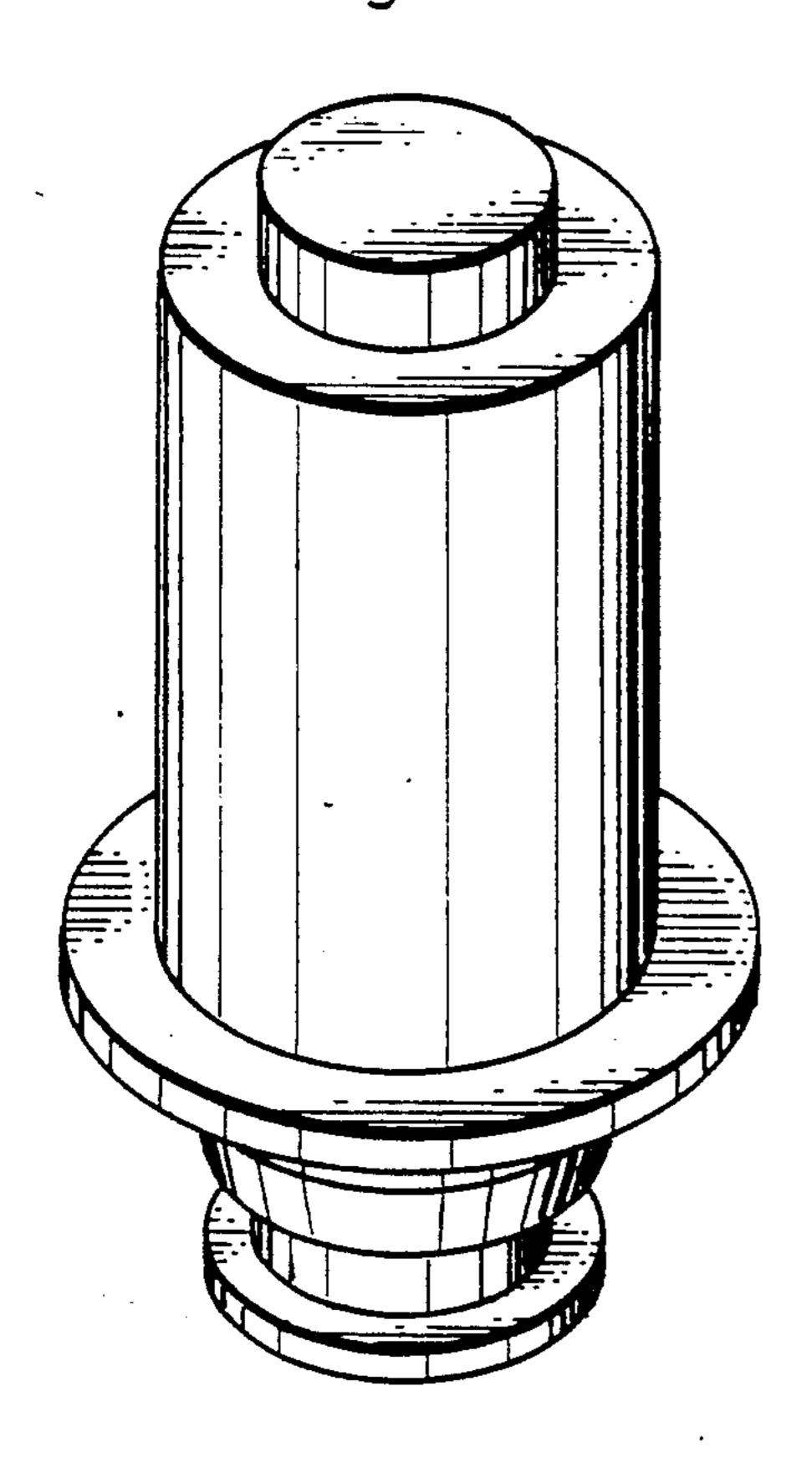


Fig. 2.

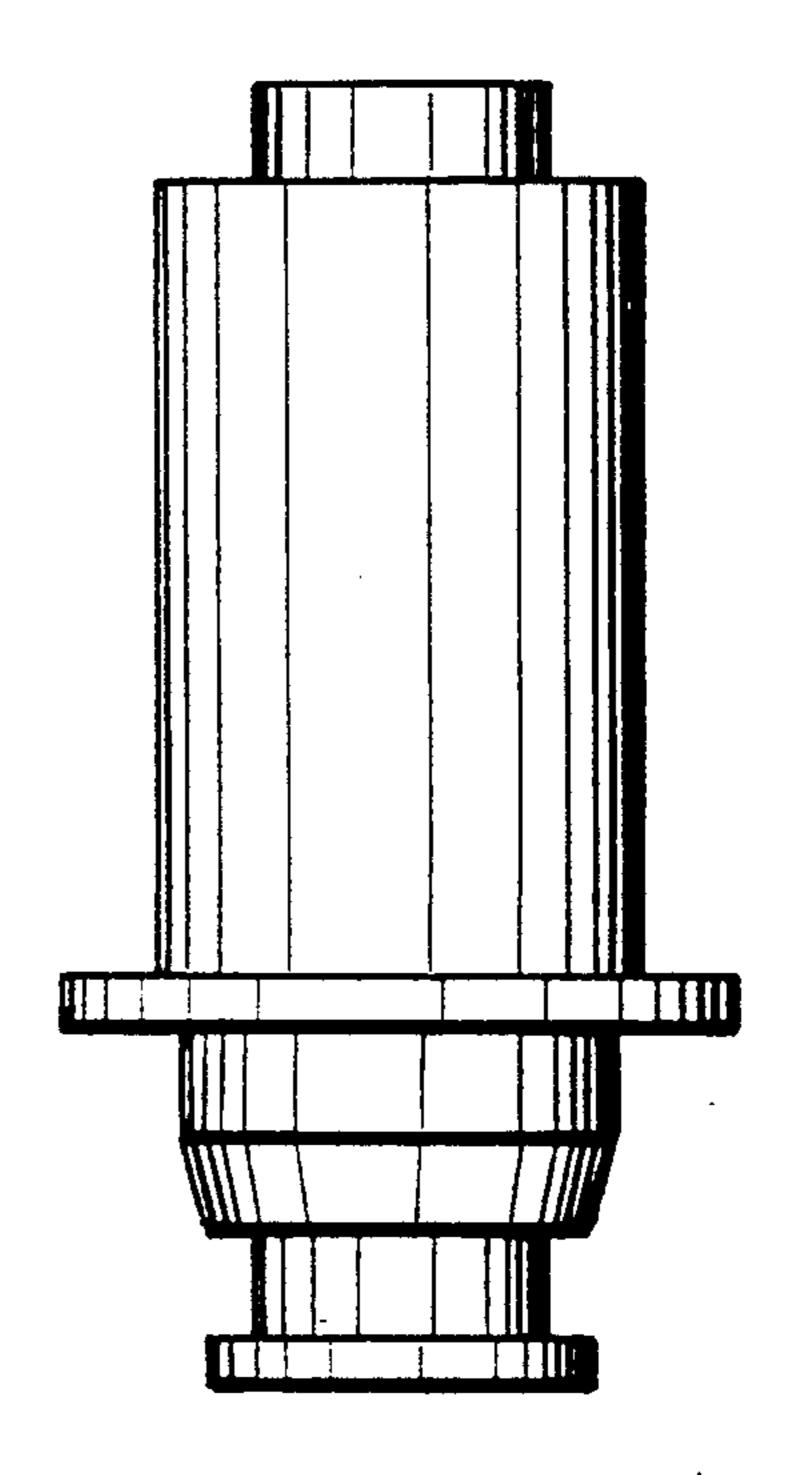


Fig. 3.

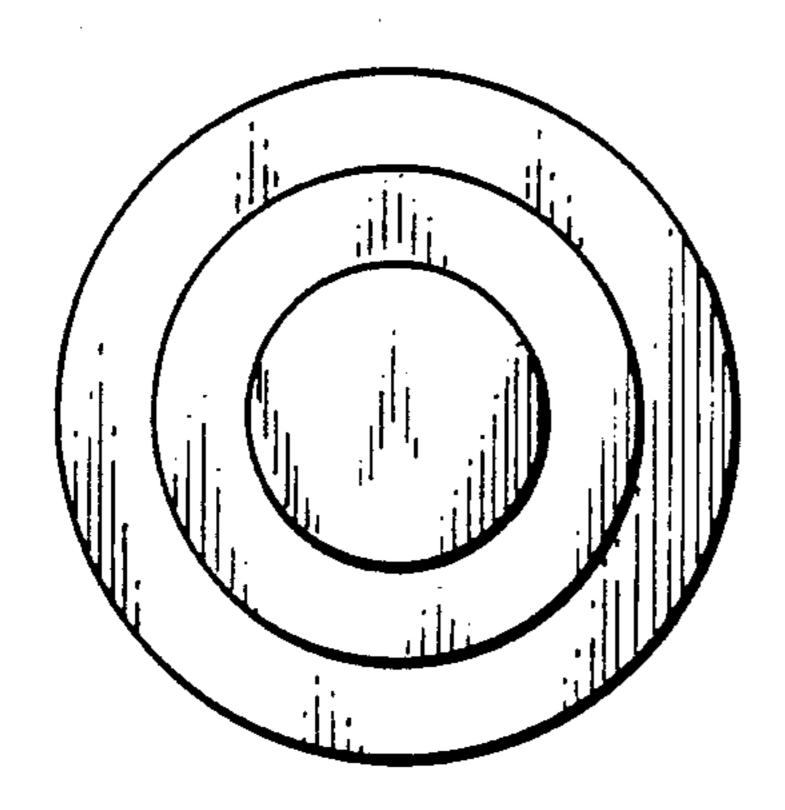


Fig. 4

